Erratum: Systematic Investigation of Anisotropic Magneto–Peltier Effect and Anomalous Ettingshausen Effect in Ni Thin films [Phys. Rev. Applied 11, 034022 (2019)]

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We identified an error in Fig. 3(b) in the original article, where the ϕ_{AMPE} image for $\theta_H = 90^\circ$ was replaced by that for $\theta_H = 0^\circ$. As shown below, we have corrected the error. All the conclusions in the original article remain unaffected. Since the analyzed θ_H dependence of ΔT_{AMPE} in the original figure is correct and consistent with the previous results shown in Ref. [1], Fig. 3(e) is not replaced in the revised figure.

FIG. 3. (a),(b) A_{AMPE} and ϕ_{AMPE} images for the U-shaped 100-nm-thick Ni film on the glass substrate for various values of θ_H , measured at $J_c = 40$ mA and $f = 25$ Hz. (c),(d) A_{AMPE} and ϕ_{AMPE} images for the U-shaped 100-nm-thick Ni film on the glass substrate for various values of f , measured at $\theta_H = 0^\circ$ and $J_c = 40$ mA. (e) θ_H dependence of ΔT_{AMPE} on the area $C_{L/R}$ for the U-shaped 100-nm-thick Ni film on the glass substrate at $J_c = 40$ mA and $f = 25$ Hz. The solid curves show the $\cos 2\theta_H$ functions for comparison with the experimental results. (f),(g) f dependence of A_{AMPE} and ϕ_{AMPE} on $C_{L/R}$ for the U-shaped 100-nm-thick Ni film on the glass substrate, measured at $\theta_H = 0^\circ$ and $J_c = 40$ mA. The data points in (e)–(g) are obtained by our averaging the A_{AMPE} and ϕ_{AMPE} values on $C_{L/R}$ defined by the squares in (a),(c). The error bars represent the standard deviation of the data in the corresponding squares.

[1] K. Uchida, S. Daimon, R. Iguchi, and E. Saitoh, Observation of anisotropic magneto-Peltier effect in nickel, *Nature* **588**, 95 (2018).

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